

MRAL2327
Series

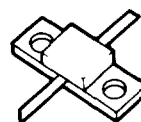
The RF Line
Microwave Power Transistors

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... designed primarily for wideband, large-signal output and driver amplifier stages in the 2.3 to 2.7 GHz frequency range.

- Designed for Class C, Common Base Power Amplifiers
- Specified 22 Volt, 2.7 GHz Characteristics:
 - Output Power — 1.3 to 12 Watts
 - Power Gain — 5.5 to 6.8 dB Min, Common Base
 - Collector Efficiency — 30 to 40% Min
- Built-In Matching Network for Broadband Operation
- Gold Metallization for Improved Reliability
- Diffused Ballast Resistors

5.5 to 6.8 dB
 2.3-2.7 GHz
1.3 TO 12 WATTS
BROADBAND
MICROWAVE POWER
TRANSISTORS



CASE 394-01, STYLE 1
 (MRA .25)

MAXIMUM RATINGS

Rating	Symbol	-1.3	-3	-6	-12	Unit
Collector-Base Voltage	V _{CE}	44				V _{dc}
Emitter-Base Voltage	V _{EB}	3.5				V _{dc}
Operating Junction Temperature	T _J	200				°C
Storage Temperature Range	T _{stg}	65 to +150				°C

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max				Unit
Thermal Resistance, RF, Junction to Case	R _{θJC}	30	16	8	4.5	C/W

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Min	Typ	Max	Unit
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OFF CHARACTERISTICS

Collector-Emitter Breakdown Voltage (I _C = 10 mA, V _{BE} = 0)	MRAL2327-1.3	V _{(BR)CES}	42	—	—	V _{dc}
(I _C = 20 mA, V _{BE} = 0)			-3	—	—	
(I _C = 50 mA, V _{BE} = 0)			-6	—	—	
(I _C = 80 mA, V _{BE} = 0)			-12	—	—	
Collector-Base Breakdown Voltage (I _C = 0.5 mA, I _E = 0)	MRAL2327-1.3	V _{(BR)CBO}	38	—	—	V _{dc}
(I _C = 1 mA, I _E = 0)			-3	—	—	
(I _C = 2.5 mA, I _E = 0)			-6	—	—	
(I _C = 8.0 mA, I _E = 0)			-12	—	—	
Emitter-Base Breakdown Voltage (I _E = 0.2 mA, I _C = 0)	MRAL2327-1.3	V _{(BR)EBO}	3.5	—	—	V _{dc}
(I _E = 0.4 mA, I _C = 0)			-3	—	—	
(I _E = 1 mA, I _C = 0)			-6	—	—	
(I _E = 2 mA, I _C = 0)			-12	—	—	
Collector Cutoff Current (V _{CB} = 22 V, I _E = 0)	MRAL2327-1.3	I _{CBO}	—	—	0.25	mAdc
	-3		—	—	0.5	
	-6		—	—	1.25	
	-12		—	—	2.0	

(continued)

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ELECTRICAL CHARACTERISTICS — continued

Characteristic	Symbol	Min	Typ	Max	Unit	
ON CHARACTERISTICS						
DC Current Gain ($I_C = 100 \text{ mA}$, $V_{CE} = 5 \text{ V}$)	MRAL2327-1.3	h _{FE}	10	—	100	
($I_C = 200 \text{ mA}$, $V_{CE} = 5 \text{ V}$)						-3
($I_C = 500 \text{ mA}$, $V_{CE} = 5 \text{ V}$)						-6
($I_C = 800 \text{ mA}$, $V_{CE} = 5 \text{ V}$)						-12
FUNCTIONAL TESTS						
Common-Base Amplifier Power Gain ($V_{CE} = 22 \text{ V}$, $P_{out} = 1.3 \text{ W}$, $f = 2.7 \text{ GHz}$)	MRAL2327-1.3	G _{pb}	5.5	—	dB	
($V_{CE} = 22 \text{ V}$, $P_{out} = 3 \text{ W}$, $f = 2.7 \text{ GHz}$)						-3
($V_{CE} = 22 \text{ V}$, $P_{out} = 6 \text{ W}$, $f = 2.7 \text{ GHz}$)						-6
($V_{CE} = 22 \text{ V}$, $P_{out} = 12 \text{ W}$, $f = 2.7 \text{ GHz}$)						-12
Collector Efficiency ($V_{CE} = 22 \text{ V}$, $P_{out} = 1.3 \text{ W}$, $f = 2.7 \text{ GHz}$)	MRAL2327-1.3	η_c	30	—	%	
($V_{CE} = 22 \text{ V}$, $P_{out} = 3 \text{ W}$, $f = 2.7 \text{ GHz}$)						-3
($V_{CE} = 22 \text{ V}$, $P_{out} = 6 \text{ W}$, $f = 2.7 \text{ GHz}$)						-6
($V_{CE} = 22 \text{ V}$, $P_{out} = 12 \text{ W}$, $f = 2.7 \text{ GHz}$)						-12

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TYPICAL CHARACTERISTICS

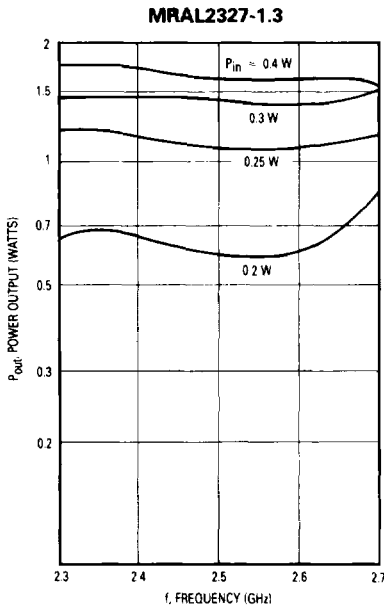


Figure 1. Power Output versus Frequency

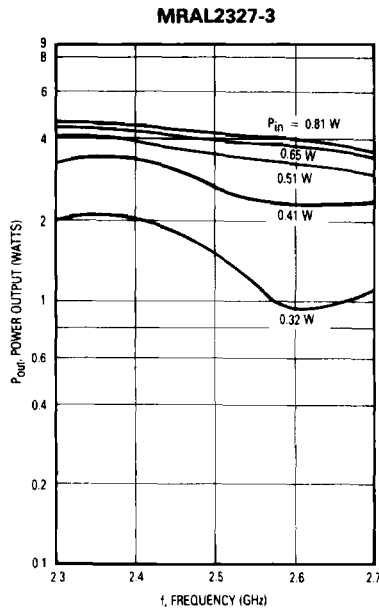


Figure 2. Power Output versus Frequency

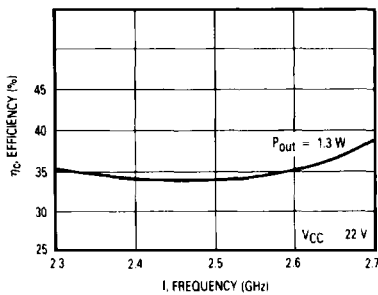


Figure 3. Collector Efficiency versus Frequency

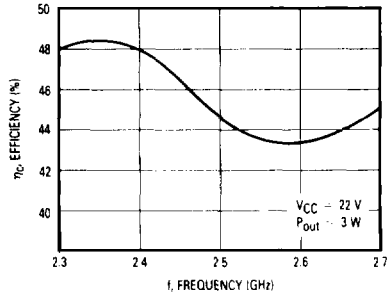


Figure 4. Collector Efficiency versus Frequency

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TYPICAL CHARACTERISTICS

MRAL2327-6

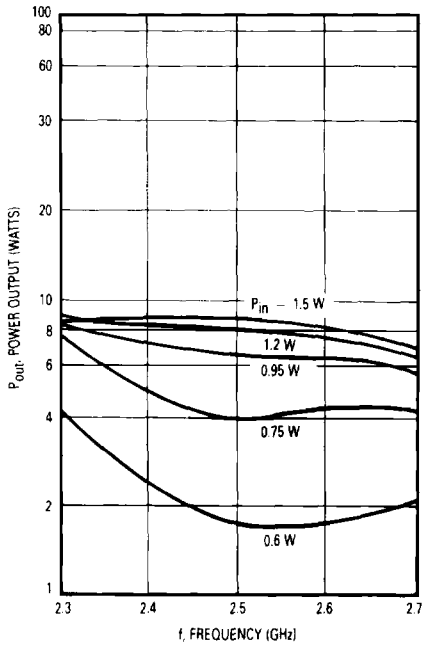


Figure 5. Power Output versus Frequency

MRAL2327-12

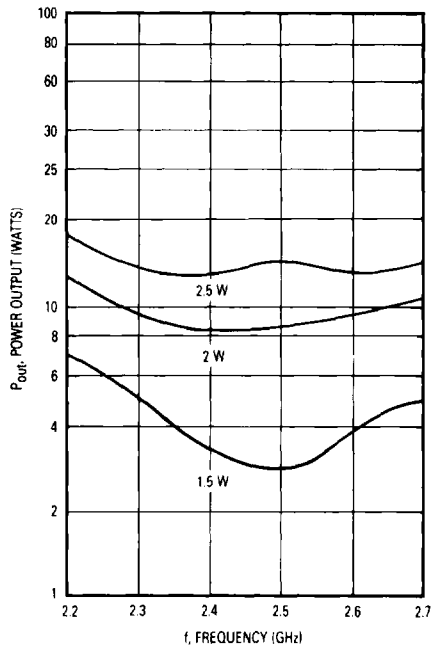


Figure 7. Power Output versus Frequency

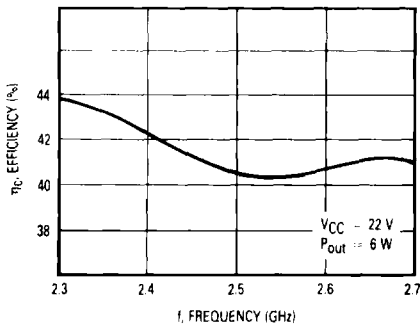


Figure 6. Collector Efficiency versus Frequency

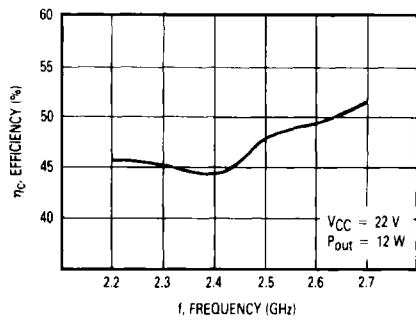
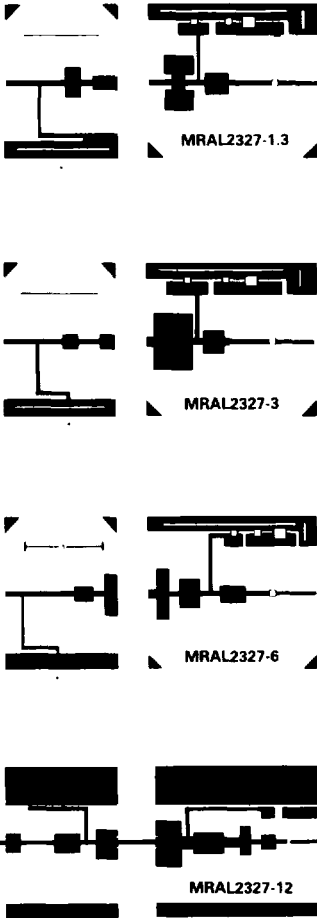


Figure 8. Collector Efficiency versus Frequency

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**Figure 9. Circuit Boards
(Not to scale.)**

Board material — 0.018" dielectric thickness Teflon fiberglass
 * Ground through to back side of board
 C1, C3 — 100 pF porcelain ceramic chip
 C4 — 0.1 μ F ceramic chip
 C5 — 50 μ F, 50 V electrolytic
 RFC1 — 5 turns #22 AWG, 0.125 dia.

The graph shown below displays MTTF in hours \times ampere² emitter current for each of the devices. Life tests at elevated temperatures have correlated to better than $\pm 10\%$ to the theoretical prediction for metal failure. Divide MTTF by I_C^2 for MTTF in a particular applications.

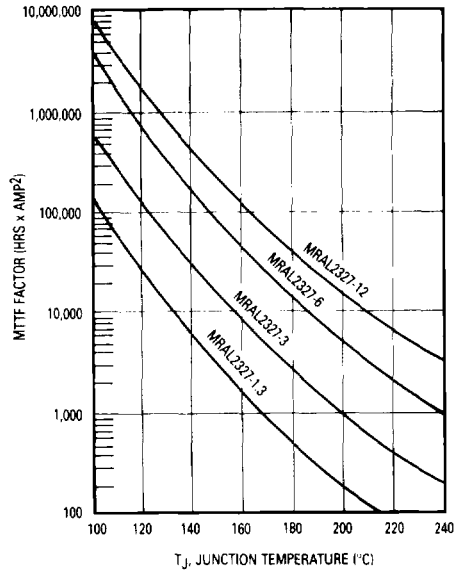


Figure 10. MTTF Factor versus Junction Temperature